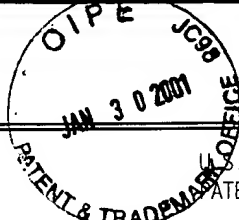


FORM PTO-1449
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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
94-C-096C2SERIAL NO.
09/517,987LIST OF REFERENCES CITED BY APPLICANT
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2812

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if appropriate)
RB	AA	4,450,620	May 29, 1984	Fuls et al	29	571	Feb. 18, 1983
	AB	4,663,825	May 12, 1987	Maeda	29	571	Sep. 25, 1985
	AC	4,676,867	Jun. 30, 1987	Elkins et al.	156	643	Jun. 6, 1986
	AD	4,775,644	Oct. 4, 1988	Szeto	437	69	Jun. 3, 1987
	AE	4,807,013	Feb. 21, 1989	Manocha	357	59	Feb. 21, 1989
	AF	4,841,347	Jun. 20, 1989	Hsu	357	23.9	Oct. 30, 1985
	AG	4,845,047	Jul. 4, 1989	Holloway, et al	437	45	Jun. 25, 1987
	AH	4,859,620	Aug. 22, 1989	Wei et al	437	44	May 20, 1988
	AI	4,937,643	Jun. 26, 1990	Deslauriers et al.	357	23.8	Jul. 27, 1987
	AJ	4,977,108	Dec. 11, 1990	Haskell	437	229	Apr. 13, 1989
	AK	5,084,419	Jan. 28, 1992	Sakao	437	228	Mar. 23, 1989
RB	AL	5,158,903	Oct. 27, 1992	Hori et al	437	45	Oct. 31, 1990

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
RB	AM	JP 60 103671	6/1985	Japan	H01L29	78	X	
RB	AN	EP 0 334 761 A1	9/1989	EPO	H01L21	28	X	
RB	AO	JP 02 009134	1/1990	Japan	H01L21	336	X	

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

RB	AP	G. Quieirolo et al., "Dpoant Activation, Carrier Mobility, and TEM Studies in Polycrystalline Silicon Films," J. Electrochem. Soc. vol. 37, no. 3, pp. 967-970 (March 1990).
RB	AQ	C.S. Pai et al., "Chemical Vapor Deposition of Selective Epitaxial Silicon Layers," J. Electrochem. So. vol. 137 no. 3, pp. 971-976 (March 1990).

EXAMINER

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Sheet 2 of 3

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U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if appropriate)
ALG	BA	5,182,619	Jan. 26, 1993	Pfiester	257	382	Sep. 3, 1991
	BB	5,192,992	Mar. 9, 1993	Kim et al	257	370	Nov. 18, 1991
	BC	5,241,193	Aug. 31, 1993	Pfiester et al	257	67	May 19, 1992
	BD	5,319,232	Jun. 7, 1994	Pfiester	257	344	Jun. 14, 1993
	BE	5,341,016	Aug. 23, 1994	Prall et al	257	412	Jun. 16, 1993
	BF	5,346,587	Sep. 13, 1994	Doan et al	156	657	Aug. 12, 1993
	BG	5,365,081	Nov. 15, 1994	Yamazaki et al	257	67	Mar. 27, 1992
	BH	5,374,574	Dec. 20, 1994	Kwon	437	44	Nov. 23, 1993
	BI	5,376,578	Dec. 27, 1994	Hsu et al	437	56	Dec. 17, 1993
	BJ	5,422,289	Jun. 6, 1995	Pierce	437	32	Apr. 27, 1992
	BK	5,434,096	Jul. 18, 1995	Chu et al	437	44	Oct. 5, 1994
	BL	5,602,056	Feb. 11, 1997	Jain et al	437	195	May 4, 1995
	BM	5,635,425	Jun. 3, 1997	Chen	438	631	May 25, 1995

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	BN							
	BO							
	BP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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	BR	

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (if appropriate)
AK	CA	5,683,924	Nov. 4, 1997	Chan et al	437	44	Jun. 7, 1995
AK	CB	5,798,278	Aug. 25, 1998	Chan et al	437	43	Aug. 25, 1998
AK	CC	5,955,770	Sep. 21, 1999	Chan et al	257	408	Sep. 21, 1999
	CD						
	CE						
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	CI						
	CJ						
	CK						
	CL						
	CM						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	CN							
	CO							
	CP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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	CR	

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